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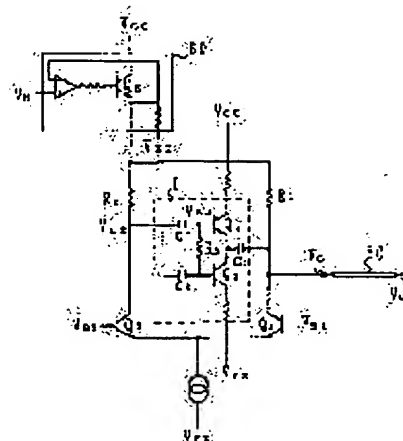
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## (54) TRANSMISSION WAVEFORM CORRECTION CIRCUIT

(57)Abstract:

**PURPOSE:** To conduct the test of an IC with high accuracy by allowing an IC tester to correct the attenuation of a signal through a transmission line between the IC tester and a DUT.

**CONSTITUTION:** When a collector voltage VC2 changes from a low level to a high level, since a signal with overshoot is inputted to bases of transistors (TRs) Q4, Q3, a TR Q2 is turned on. Through the operation, a capacitor C3 is released and the voltage across the capacitor is subtracted from a driver output voltage. As a result, an unsharpened pulse waveform with overshoot/ undershoot on a transmission line 50 is corrected and the resulting signal is inputted to a DUT.



## LEGAL STATUS

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